



# Silent Data Corruptions at Scale

EDPS 2023

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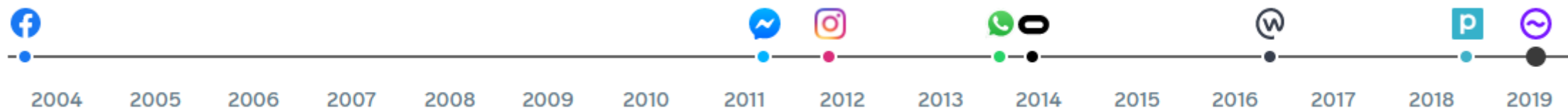
Meta Infrastructure

Menlo Park, CA, USA



## Family MAP : 3.81B

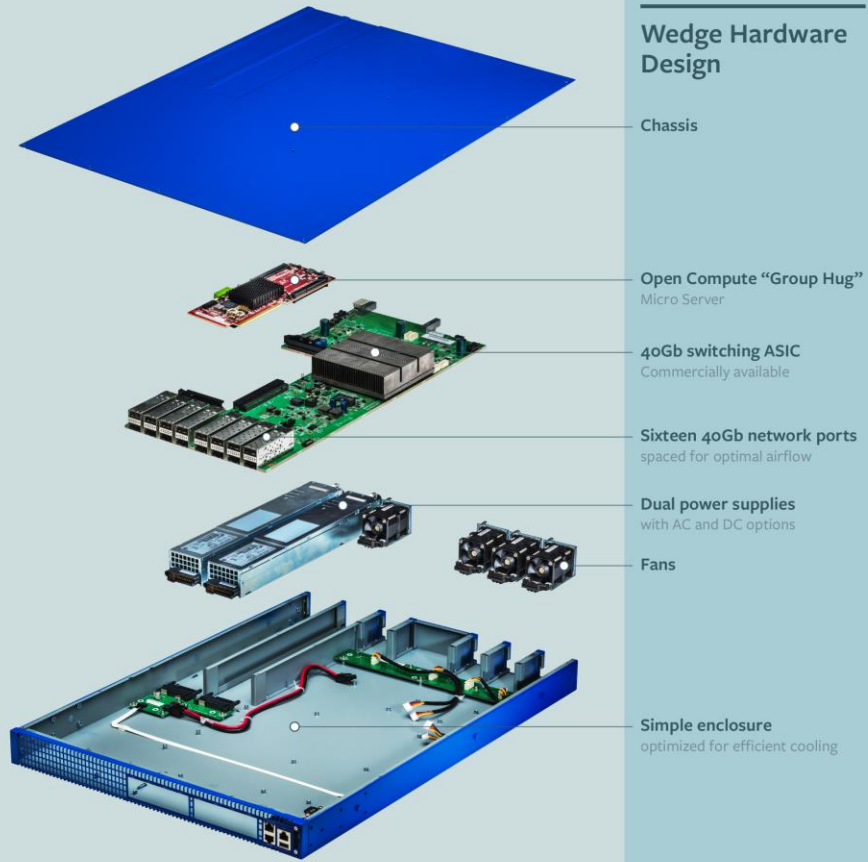
Globally, there are more than 3.81B people using Facebook, WhatsApp, Instagram or Messenger each month.



\*MAP - Monthly Active People  
Source: Meta Platforms Inc. Q1 2023



## Wedge Hardware Design

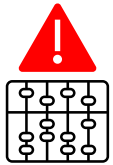


# Silent Data Corruptions

$$(1.1)^{53} = 0$$

$$(1.1)^{53} = 0$$

## Silent Errors in Compute Units



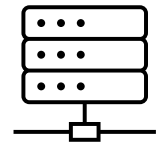
Defects  
in silicon



Hard to  
detect



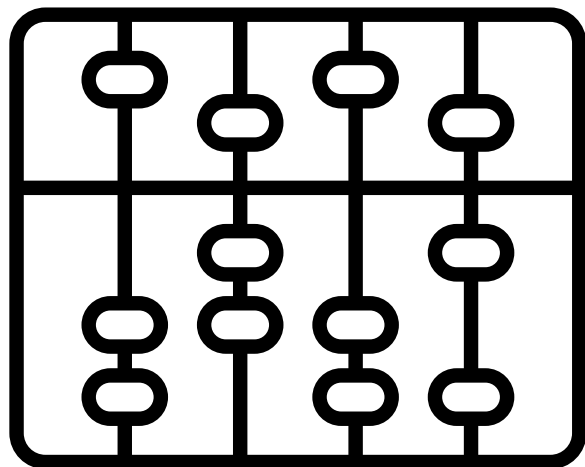
Undetected for  
months/years



Significant impact  
to services



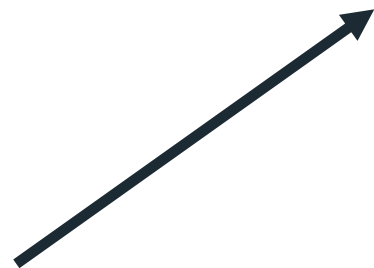
# What makes SDCs different ?



Faulty Device



Typical Fault Management



~~System Crashes~~  
ECC mechanisms



~~System Logs~~  
Standard RAS  
mechanisms



~~Machine Check~~  
registers / counters

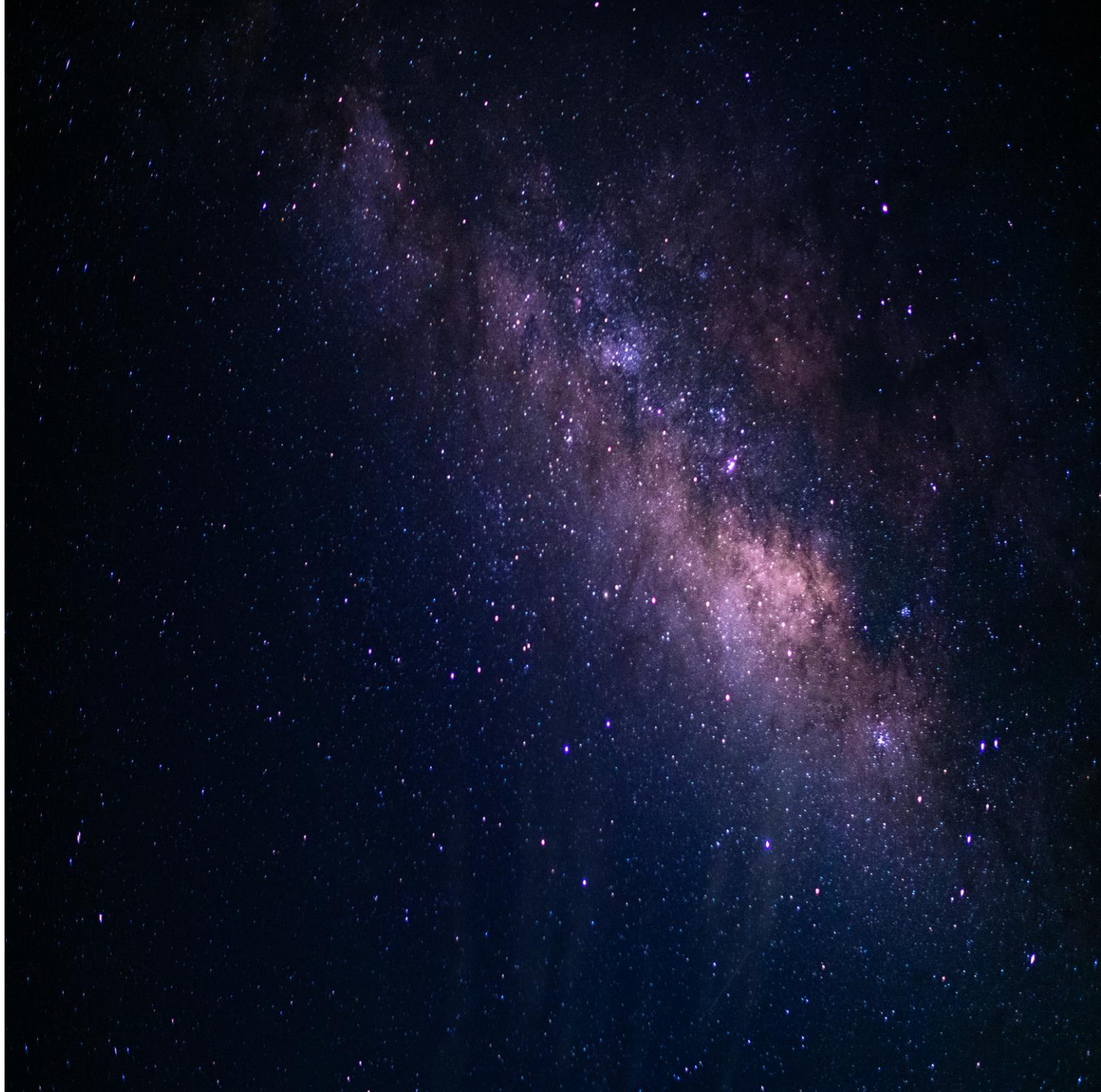
In the case of silent errors, none of these are available

But wait ....

Cosmic Rays ?

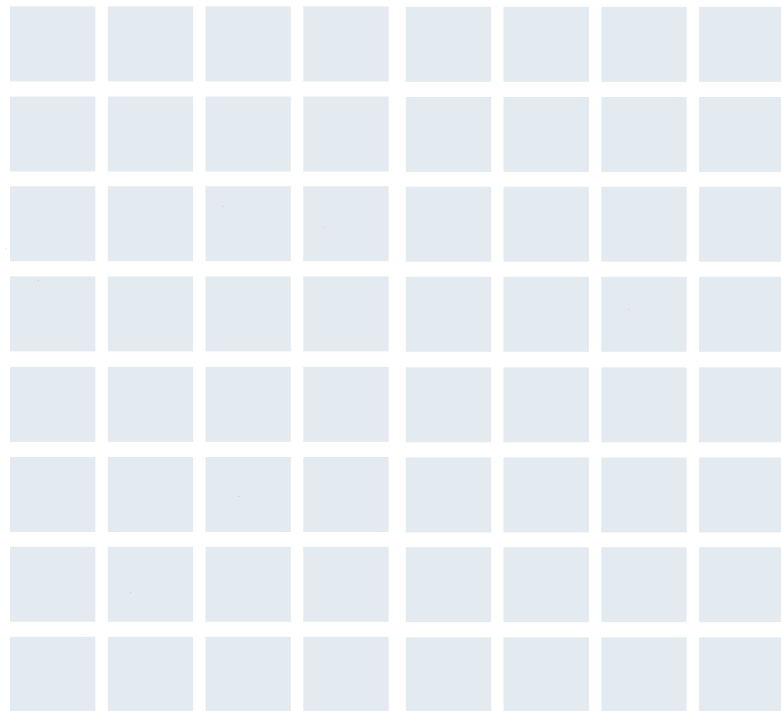
Pentium FDIV ?

Isn't this a solved problem ?



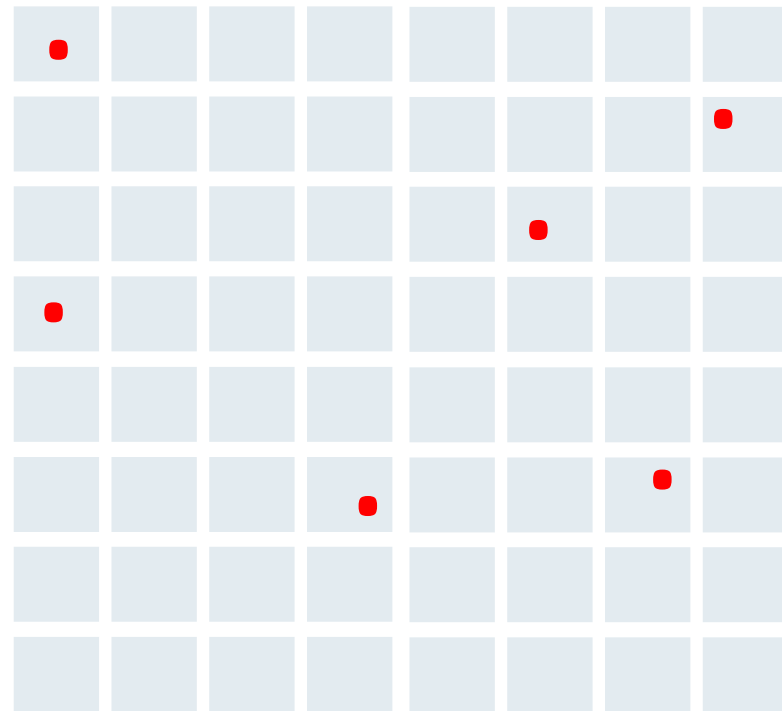
# Cosmic Ray induced faults

1 fault in a million devices



# Silent Data Corruptions

1 fault in a thousand devices



POSTED ON FEBRUARY 23, 2021 TO DATA INFRASTRUCTURE

Mitigating the effects of silent data corruption at scale

A landscape photograph featuring three large, cylindrical hay bales in a field. The bales decrease in size from left to right. The sky is a mix of blue, orange, and purple, with a vibrant rainbow arching across the upper right portion. The foreground is filled with golden-brown grass.

**A needle in haystack situation**

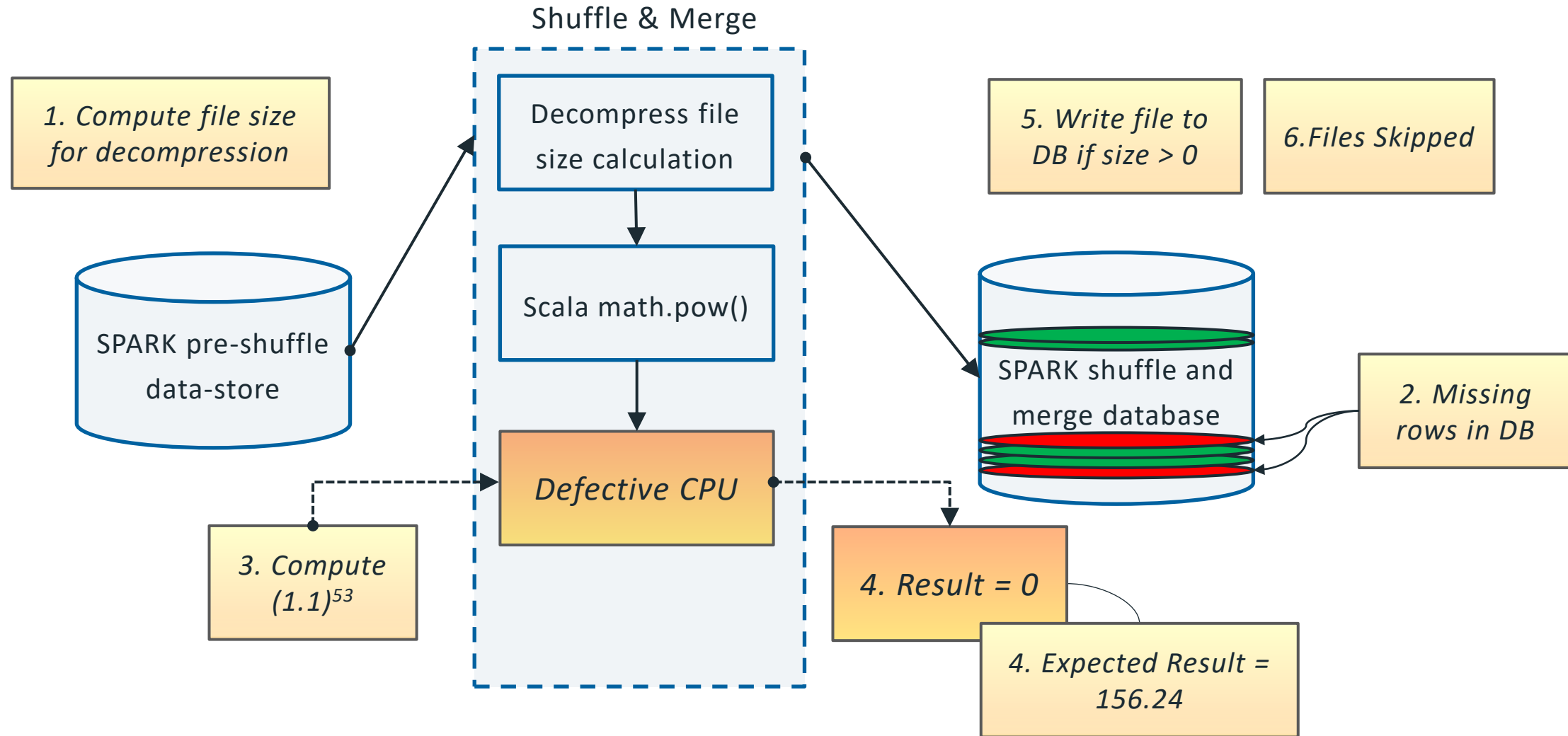
*..... where the needle keeps moving, changing size and shape*

*..... and the haystack gets larger every day*

**How did we find  
these elusive SDCs?**



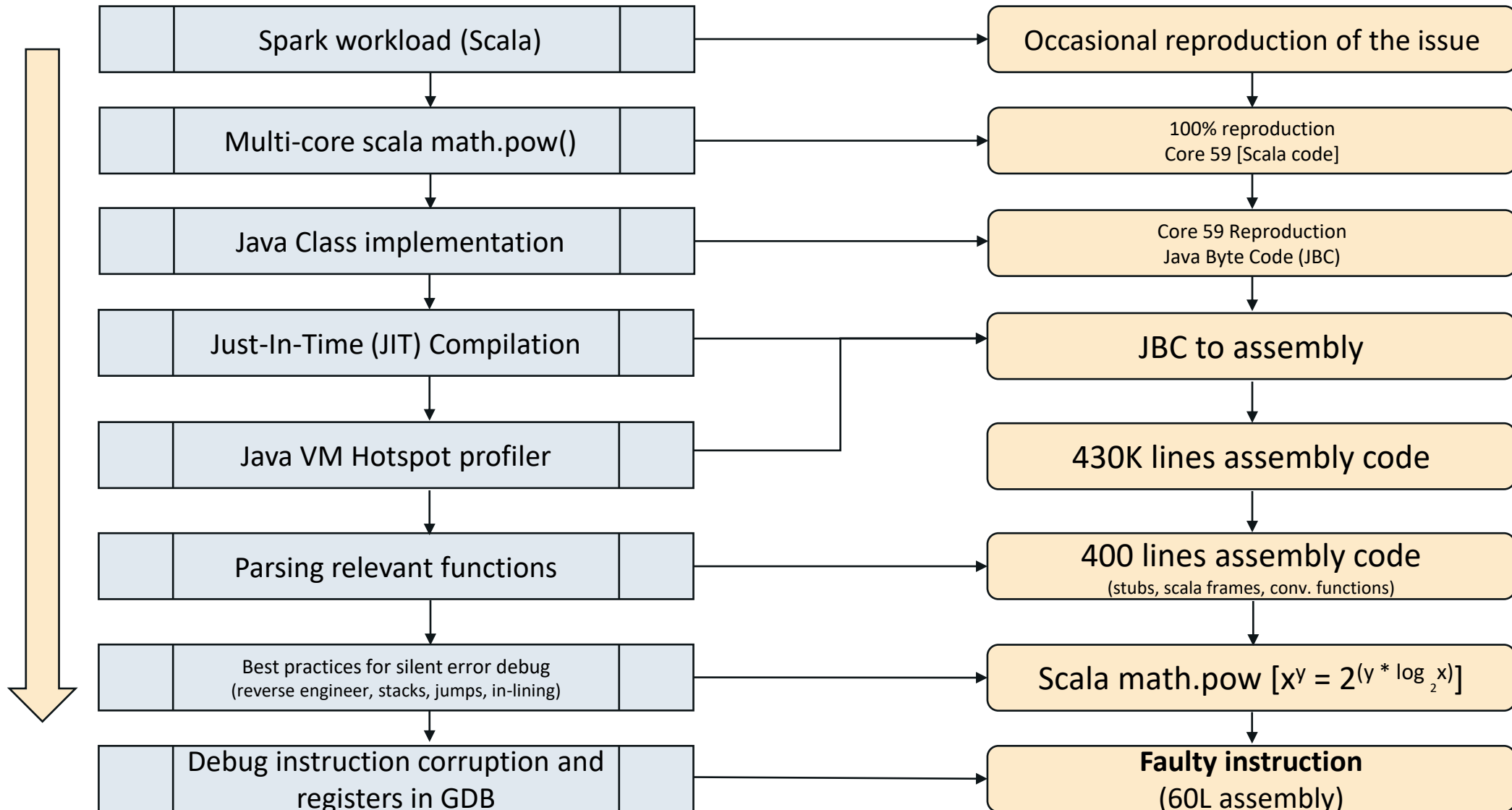
# CPU Silent Data Corruption (Case Study in SPARK DB)



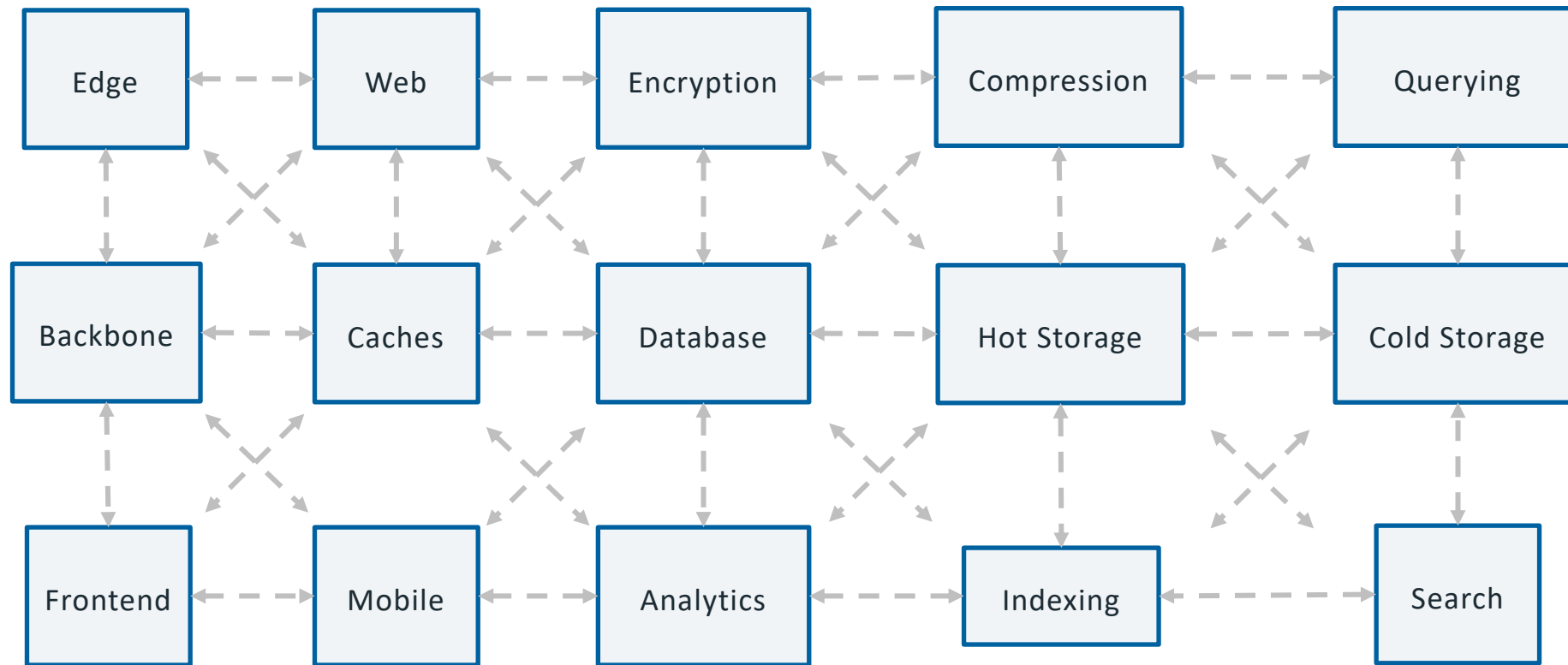
An example of a single faulty CPU encountering silent data corruptions

**Result: Missing rows in a Spark Database Application (Highest Infra Severity Event)**

# Isolating the faulty instruction down to 60 lines assembly!



## 3.8B MAP translates to billions of computations and interactions every day

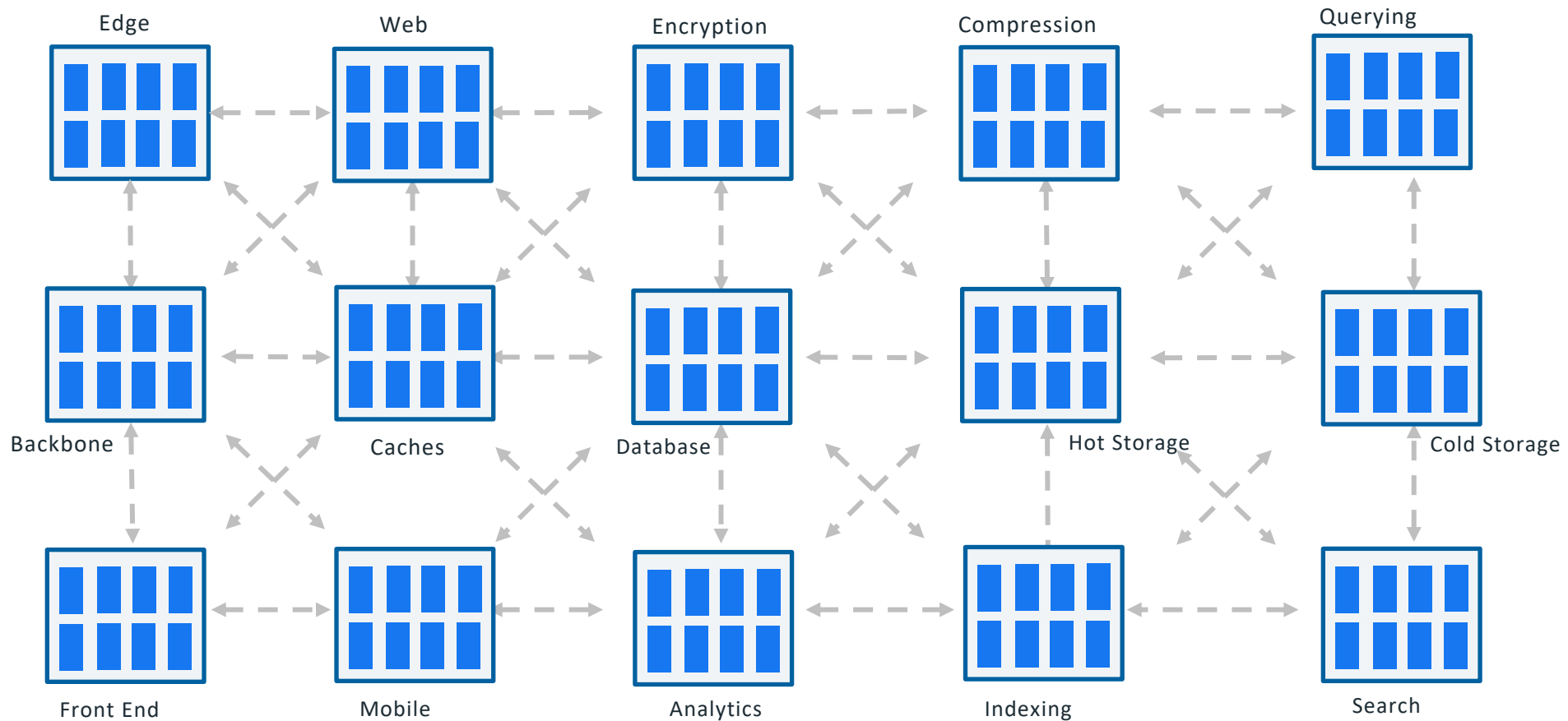


Failures can lead to contained and uncontained fan-outs

*\*illustrative only large-scale system diagram (not an architecturally directional flow representation)*



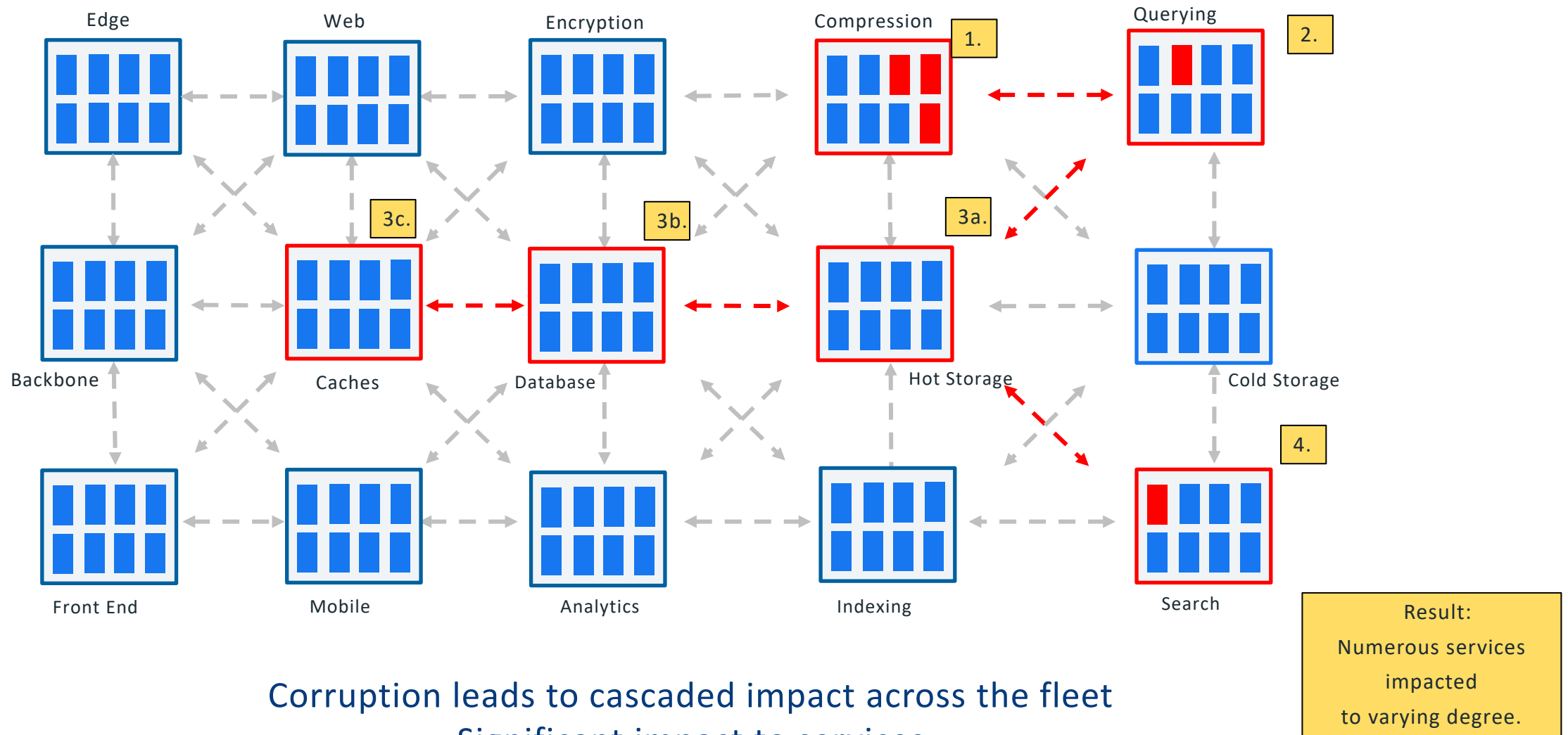
# Systems at Scale



At a server level, services translate to numerous machines  
executing transactions with large fanout

*\*All machines assumed to be of the same size for illustration*

# Systems at Scale



*\*All machines assumed to be of the same size for illustration*

# Detecting silent data corruptions

Why is this a hard problem ?



Data Randomization

Eg:  $3 \times 5 = 15$  but  $3 \times 4 = 10$



Electrical Variations (V, I, f)

Eg:  $3 \times 5 = 15$ , but repeated  
 $3 \times 5 \neq 15$  across device characteristics



Environmental Variations

(changing T, regional factors etc)

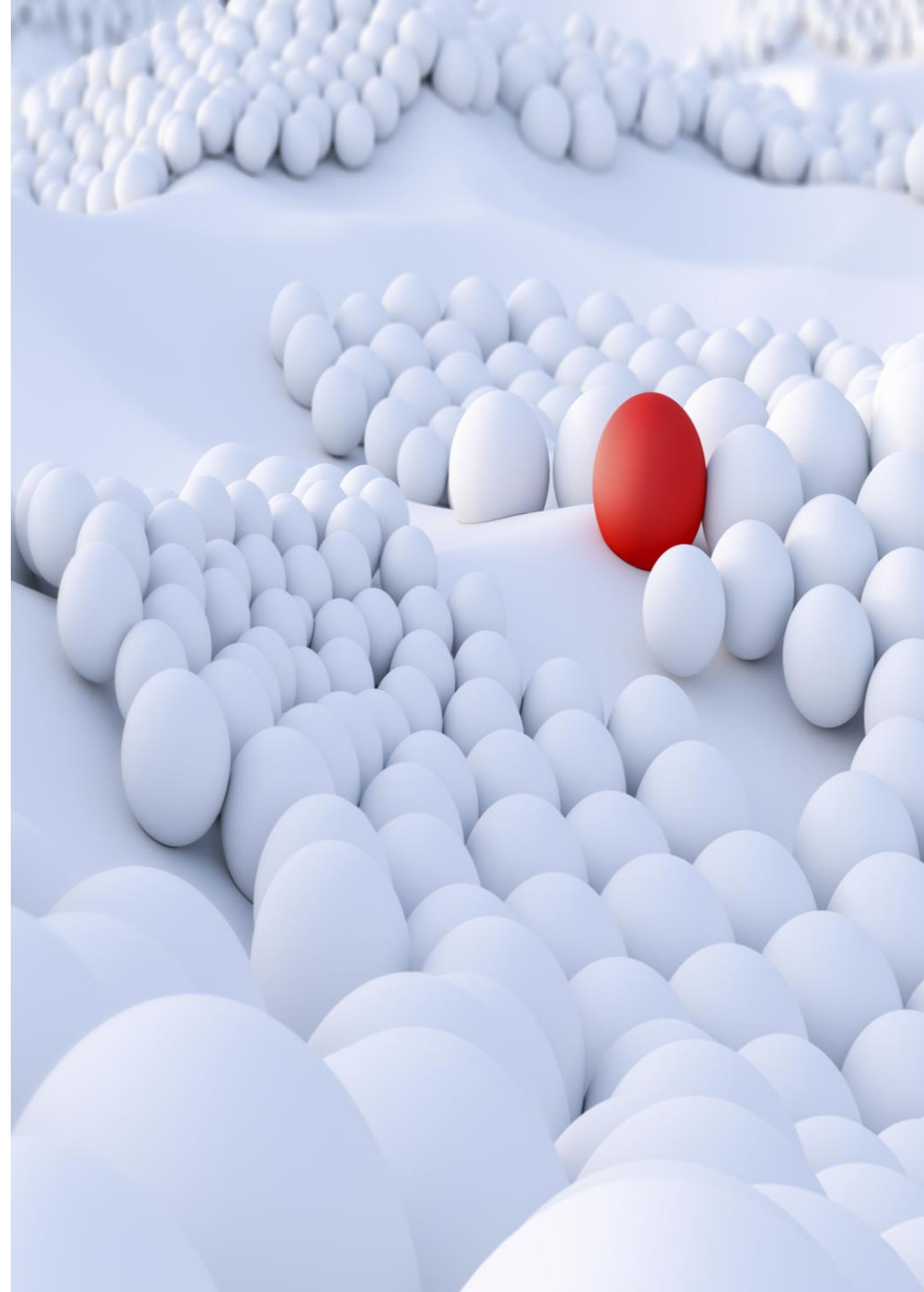
Eg:  $3 \times 5 = 15$ , but repeated  
 $3 \times 5 \neq 15$  in all regions



Lifecycle Variations

Eg:  $3 \times 5 = 15$  today  
but tomorrow  $3 \times 5 = 13$

**From 1 SDC to 100s –  
How did we scale our  
approach?**

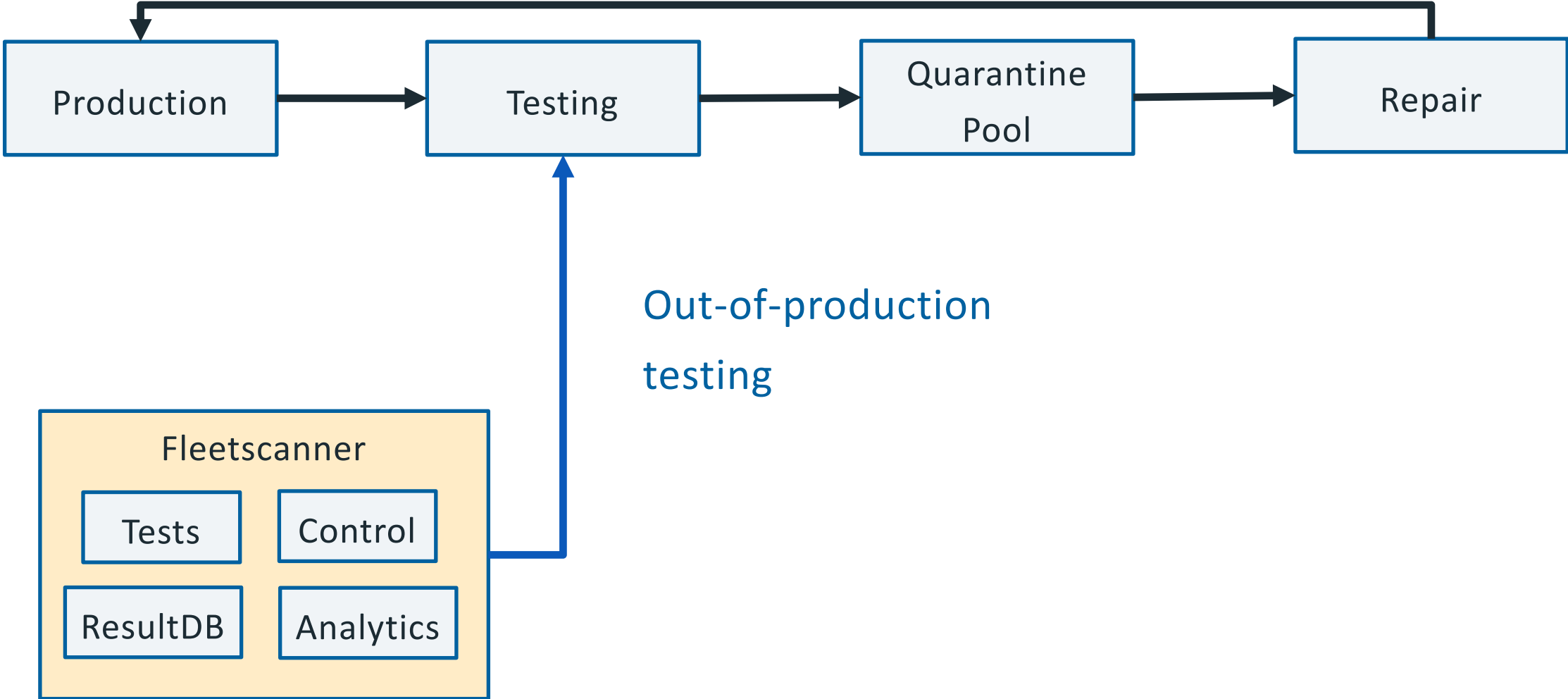


# Test continuously in the fleet

- Fleetscanner (Out-of-production testing)
- Ripple (In-production testing)

In addition to – testing at the manufacturer and at datacenter intake.

# Test continuously in the fleet (Fleetscanner)



# Fleet Scanner

Taking pitstops to run tests!

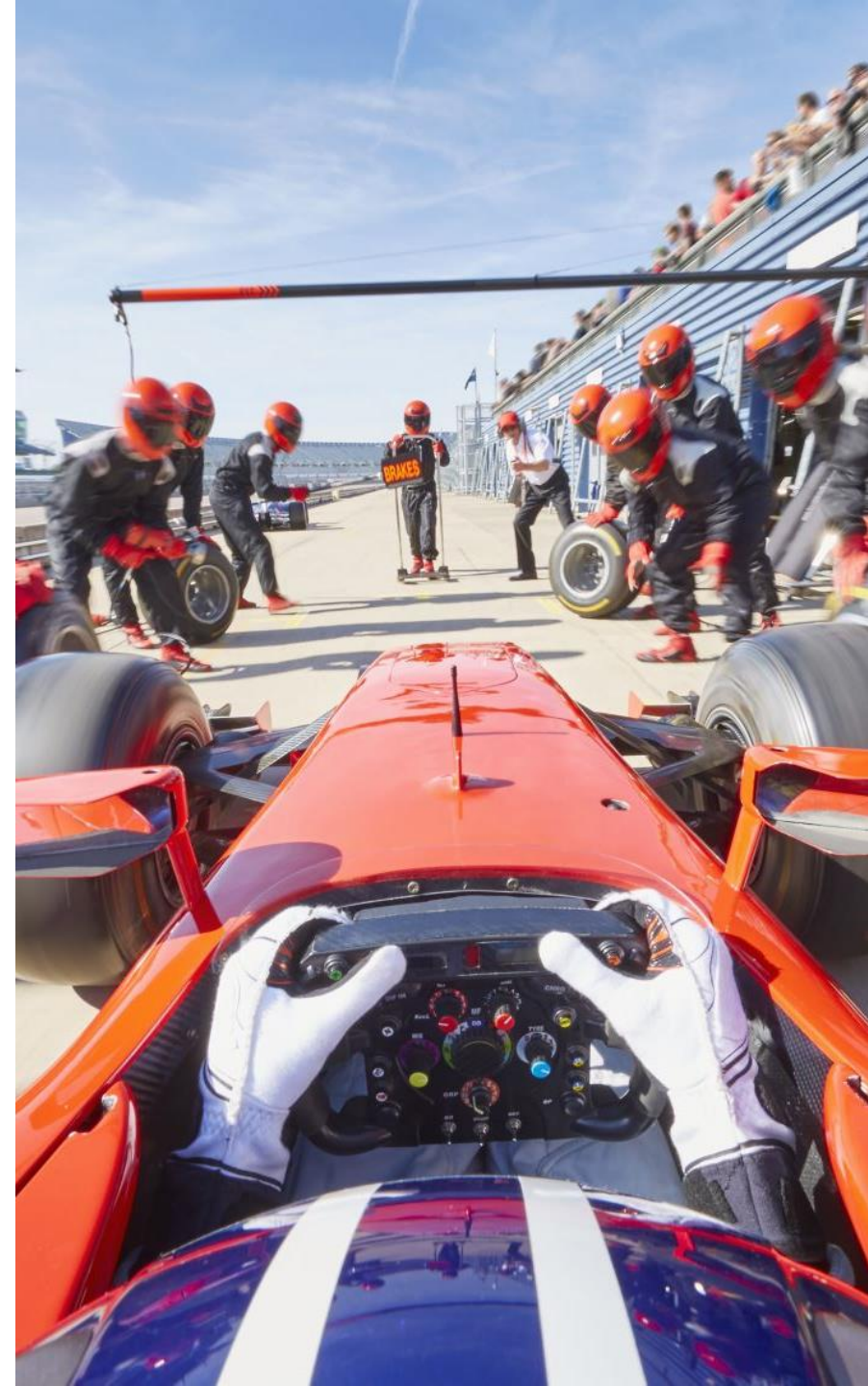
- Non-Production States
- Run directed tests
- Test time: Order of minutes
- Time to fleet coverage: 6 months
- 100s of devices detected with silent errors

## 4B

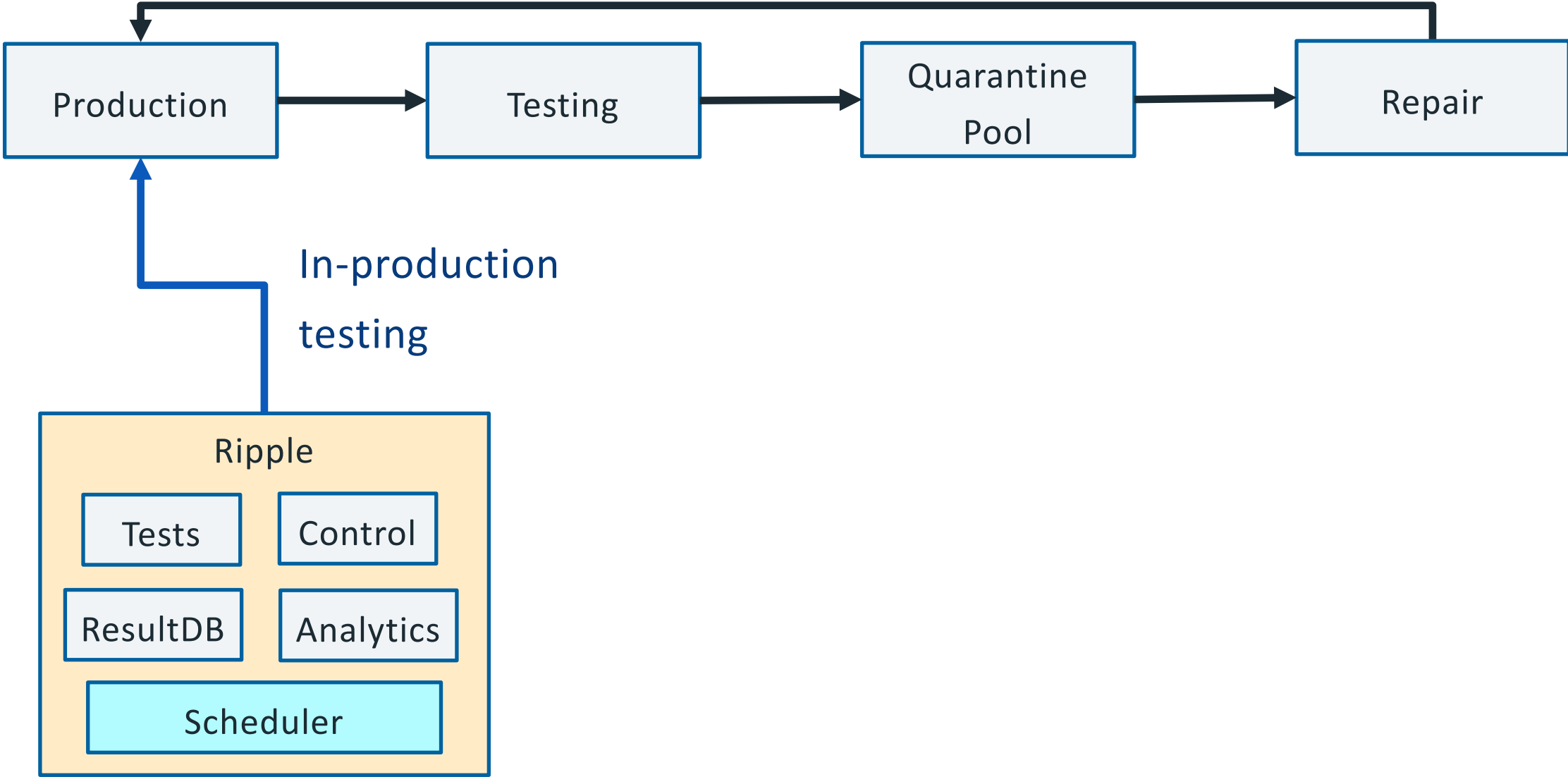
fleet seconds (lifetime)

FLEET TESTING TIME

**BUT THIS IS TOO SLOW ACROSS A LIVE FLEET.....**



# Test continuously in the fleet (Ripple)





# Ripple testing

Testing along with workloads

- Workload colocation
- In-production tiny tests
- Test time: Order of milliseconds
- Time to fleet coverage: 15 days

# 100M

fleet seconds per month

**FLEET TESTING TIME**

**BOTH METHODS OF TESTING PROVIDE UNIQUE COVERAGE!**



POSTED ON MARCH 17, 2022 TO PRODUCTION ENGINEERING

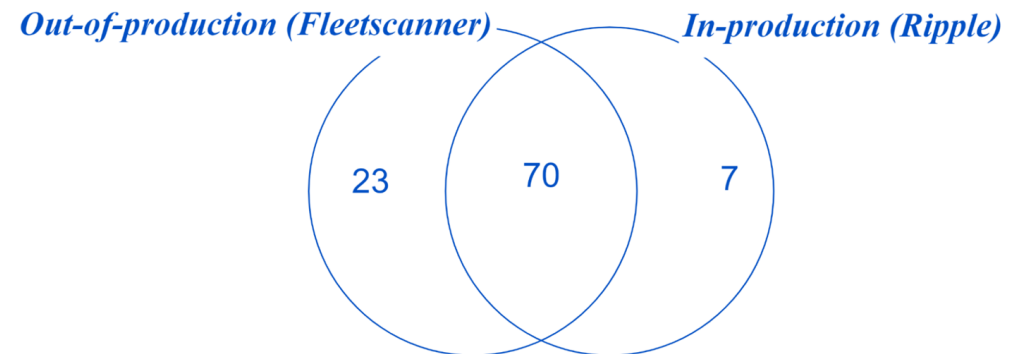
Detecting silent errors in the wild:  
Combining two novel approaches to  
quickly detect silent data corruptions at  
scale

# Key Results

3 years of infrastructure testing using both mechanisms (for a large defect family)

Metric	Fleetscanner	Ripple
Test Iterations	~68M (lifetime)	~2.5M (per month)
Performance aware	No	Yes
Time to equivalent SDC coverage	~ 6 months (70%)	~ 15 days (70%)

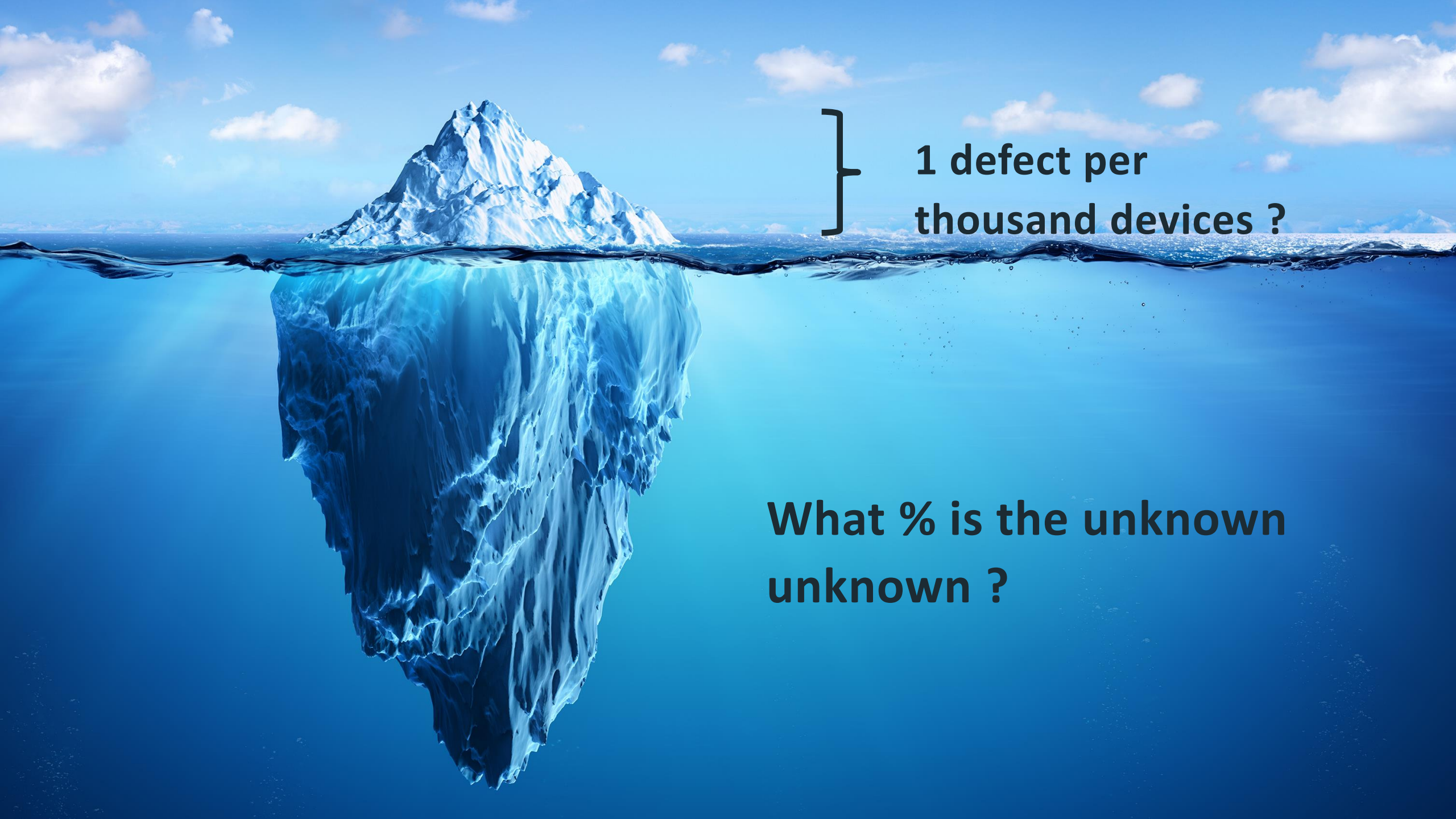
*Detectable silent data corruptions*



# Interesting observations:

$Int[(1.1)^3] = 0, \textit{expected} = 1.$   
 $Int[(1.1)^{107}] = 32809, \textit{expected} = 26854.$   
 $Int[(1.1)^{-3}] = 1, \textit{expected} = 0.$

- . Compiler and optimization dependent.
- . Impacting computations involving non-zero operands, results, with varying degrees of precision.
- . Impacts wide variety of applications.
- . Impacts multiple instruction types and functional subblocks
- . Vectors, Floating computations, large data moves, gather-scatter ops, encryption, shared memory coherency, string corruptions etc.
- . Instances of impact in coldstorage (backups), presto (queries) and kernel code etc.



**1 defect per  
thousand devices ?**

**What % is the unknown  
unknown ?**

# What's next ? – Dealing with SDCs

## HARDWARE DESIGN STRATEGIES

Fault tolerant designs

Data Protection  
Priorities

Specialized Screening

@scale collaboration

## PRODUCTION FLEET STRATEGIES

Manufacturing  
validation

Out of production  
testing

In production testing

## SOFTWARE & APPLICATION STRATEGIES

Algorithmic Fault  
Tolerance

Probabilistic  
Redundancy

Software fault  
correlation

With increased silicon density and technology scaling,  
we are more likely to see silent data corruptions in future CPUs and ASICs.

Silent errors are a foundational  
computing problem!

Thank You!!

